

# INVERSE ELASTIC SCATTERING WITH ADAPTIVE FE MESHES

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# AIM

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- Numerically model the forming of images in a Transmission Electronic Microscope (TEM)

➡ forward problem

- From given images, identify defects within the studied sample

➡ inverse problem



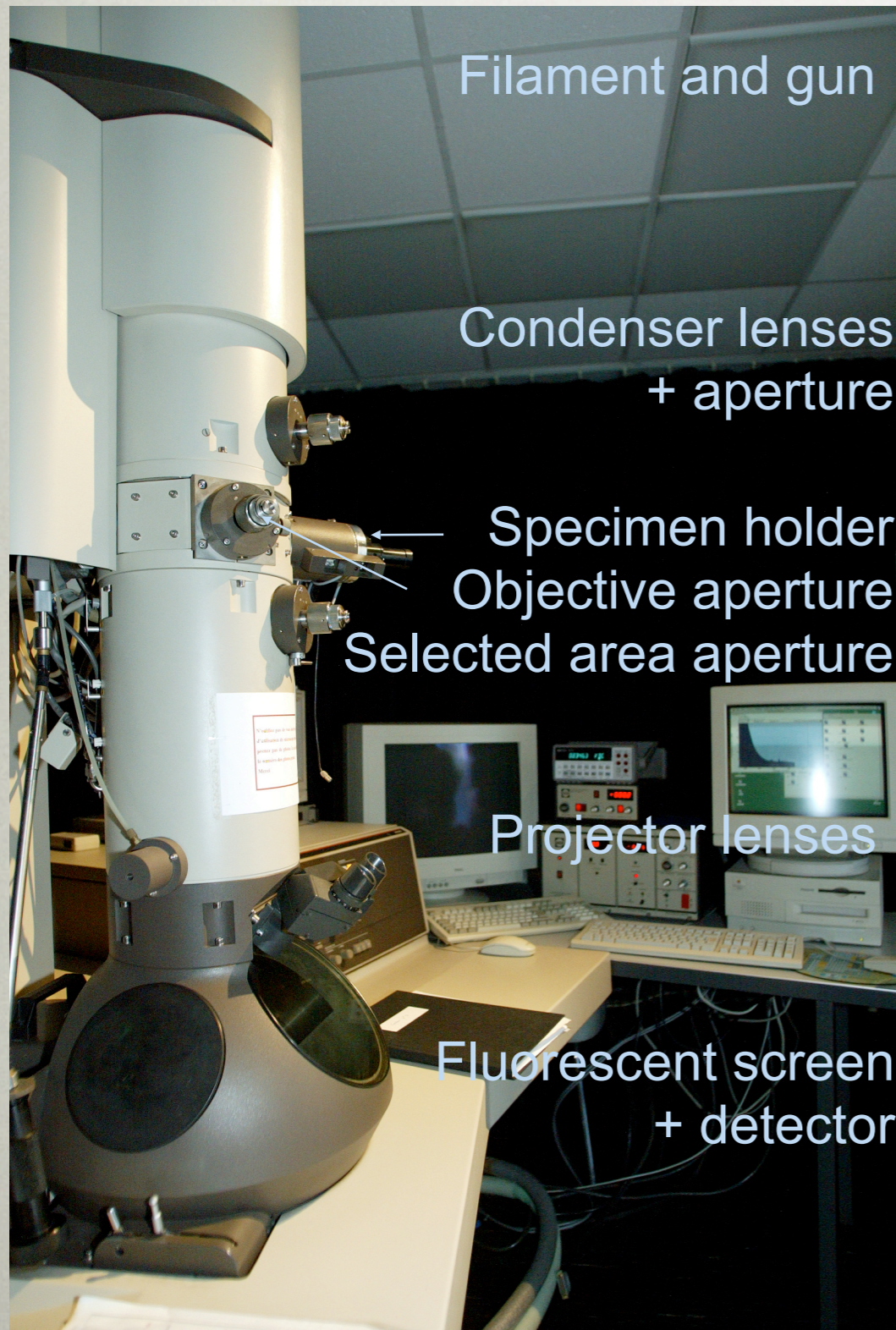
# OUTLINE

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- TEM forward scattering
  - TEM principles
  - TEM forward scattering
- Inverse scattering
- Results



# TEM PRINCIPLES



## Philips CM20-UT

$$E_c = 200 \text{ keV}$$

$$v = 0.70 c$$

$$\lambda = 2.51 \cdot 10^{-12} \text{ m}$$

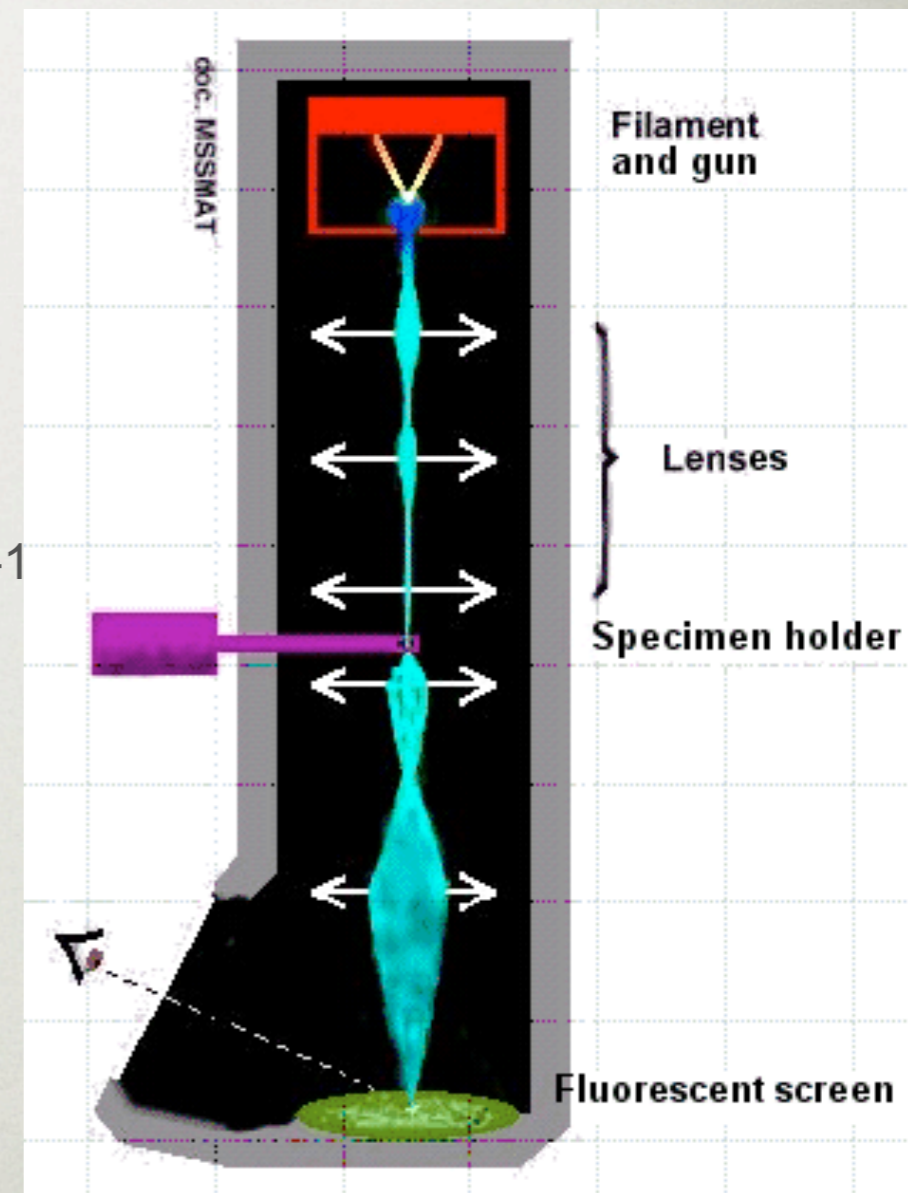
$$k_i = 2.51 \cdot 10^{12} \text{ rad.m}^{-1}$$

$$\beta = 13 \text{ mrad}$$

$$C_s = 0.5 \text{ mm}$$

$$\delta = 0.19 \cdot 10^{-9} \text{ m}$$

$$\theta_{\text{max}} \sim \pm 0.25 \text{ rad}$$





# TEM PRINCIPLES

- Incident electron:

- plane wave

$$\psi_i(\mathbf{x}) = \tilde{\psi}_i \exp(i\mathbf{k}_i \cdot \mathbf{x})$$

Source crossover (point) A

Parallel illumination

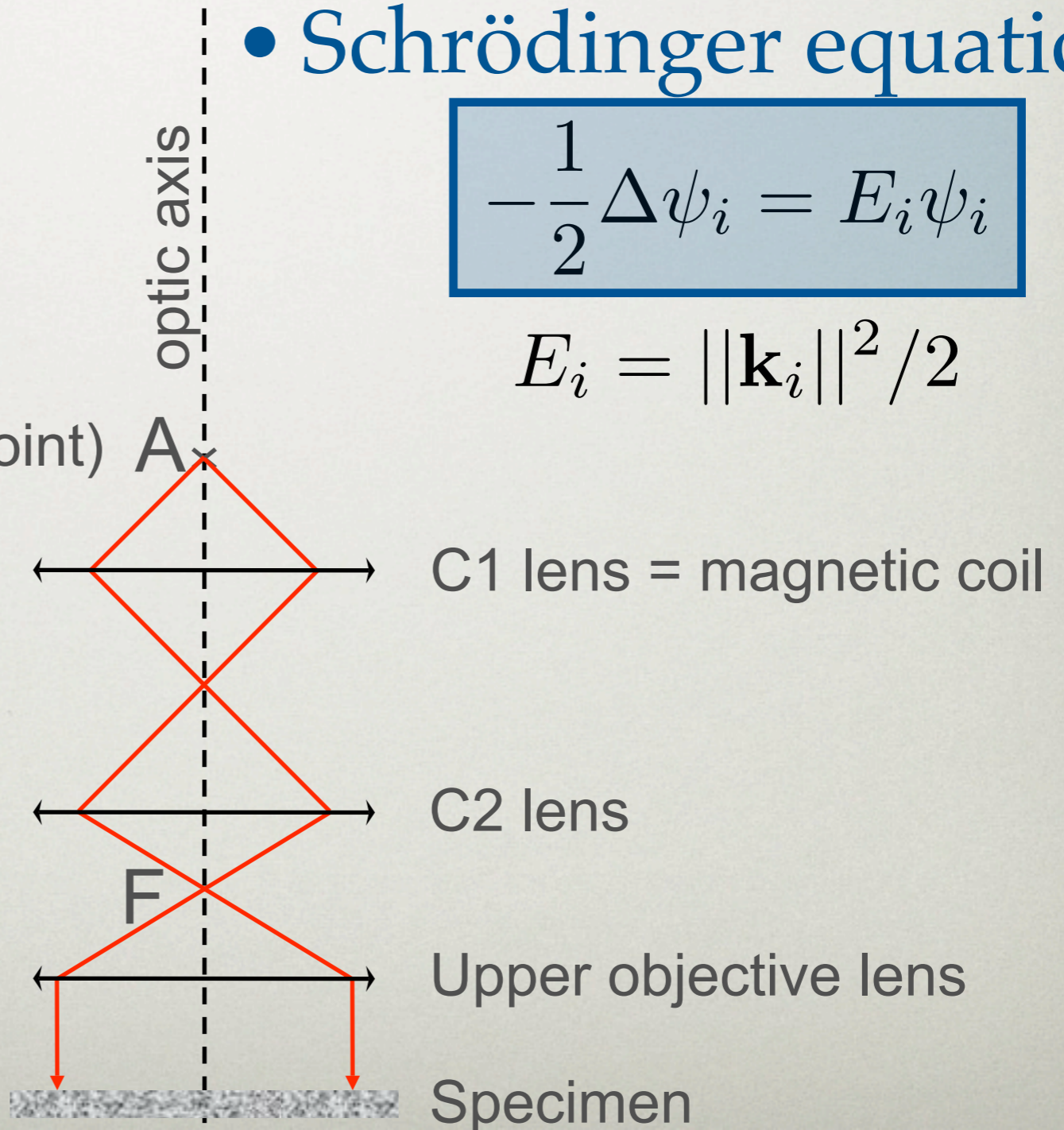
$$\theta = 0$$

Image of A through C1 and C2  
= focal point of objective lens

- Schrödinger equation:

$$-\frac{1}{2}\Delta\psi_i = E_i\psi_i$$

$$E_i = \|\mathbf{k}_i\|^2/2$$



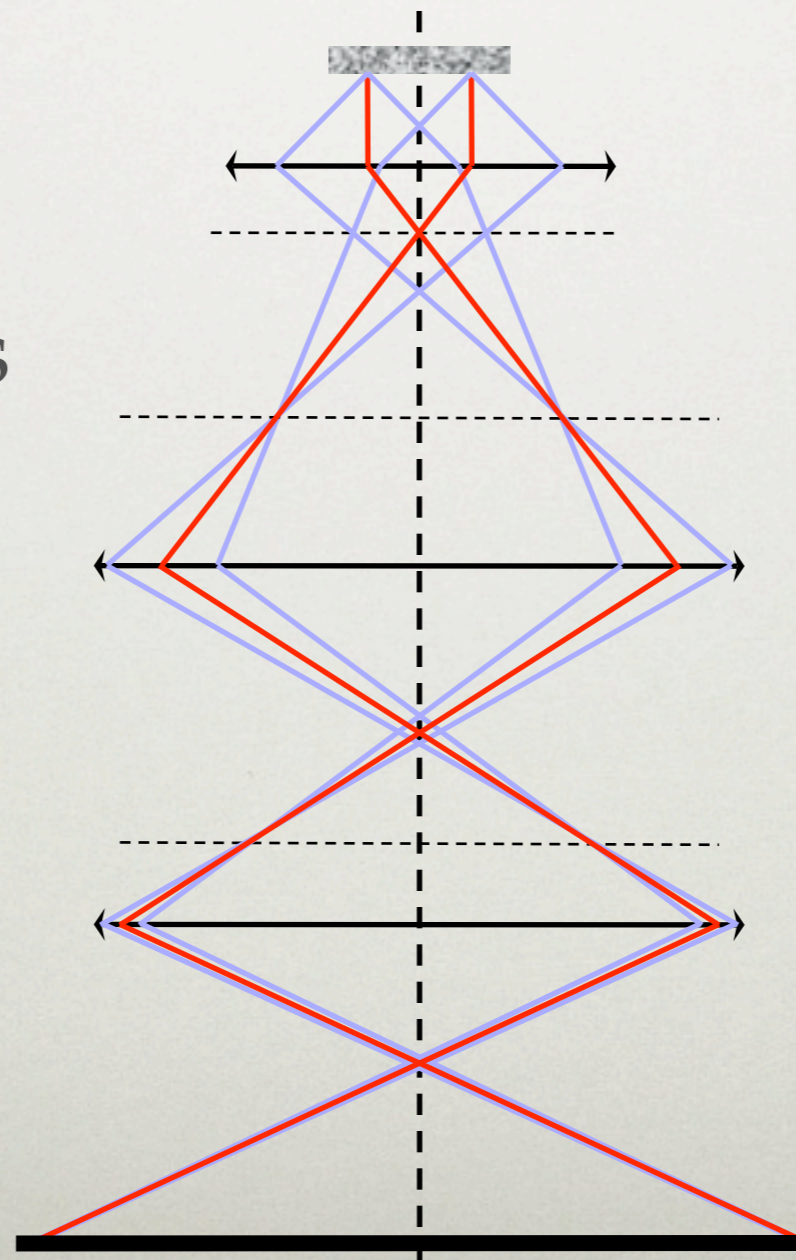


# TEM PRINCIPLES

- Outgoing wave

## Forming images

- transmitted beam
- diffracted beam (Bragg law)



Specimen

Objective lens

Back focal plane

≡ diffraction pattern

Image plane

≡ intermediate image

Intermediate lens

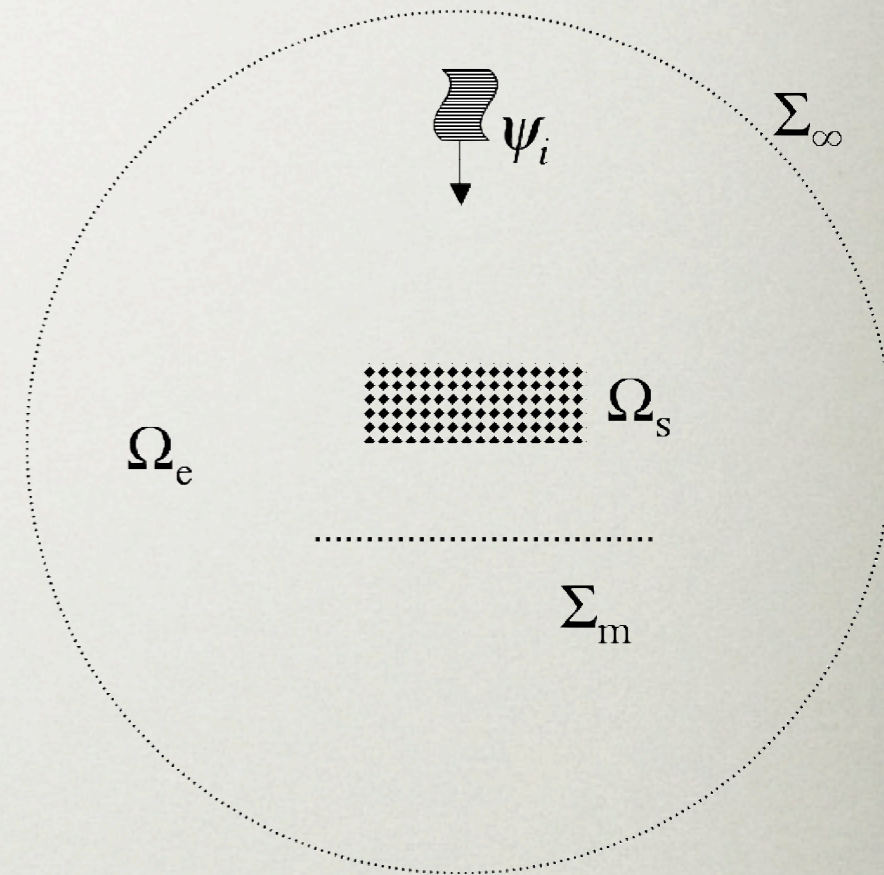
Projector lens

Screen ≡ final image



# TEM FORWARD SCATTERING

- Schrödinger equation:
  - for incident electron only [Wang 1995]
  - assumptions + decompositions  
 $\psi = \psi_i + \psi_d$  ← diffracted field
  - paraxial approximation  
 $\psi_d(\mathbf{x}) = \tilde{\psi}_d(\mathbf{x}) \exp(i\mathbf{k}_i \cdot \mathbf{x})$



$$\frac{1}{2} \Delta \tilde{\psi}_d + i\mathbf{k}_i \cdot \nabla \tilde{\psi}_d = V \tilde{\psi}_d \text{ in } \Omega_e$$

$$\frac{\partial \tilde{\psi}_d}{\partial \mathbf{n}} = i(\|\mathbf{k}_i\| - \mathbf{k}_i \cdot \mathbf{n}) \tilde{\psi}_d \text{ on } \Sigma_\infty$$

[Popov 2006]



# EXAMPLE ON $\alpha$ -IRON

## [011] AXIS

- FE simulation on a 2D very thin sample

- Yukawa potential for the sample

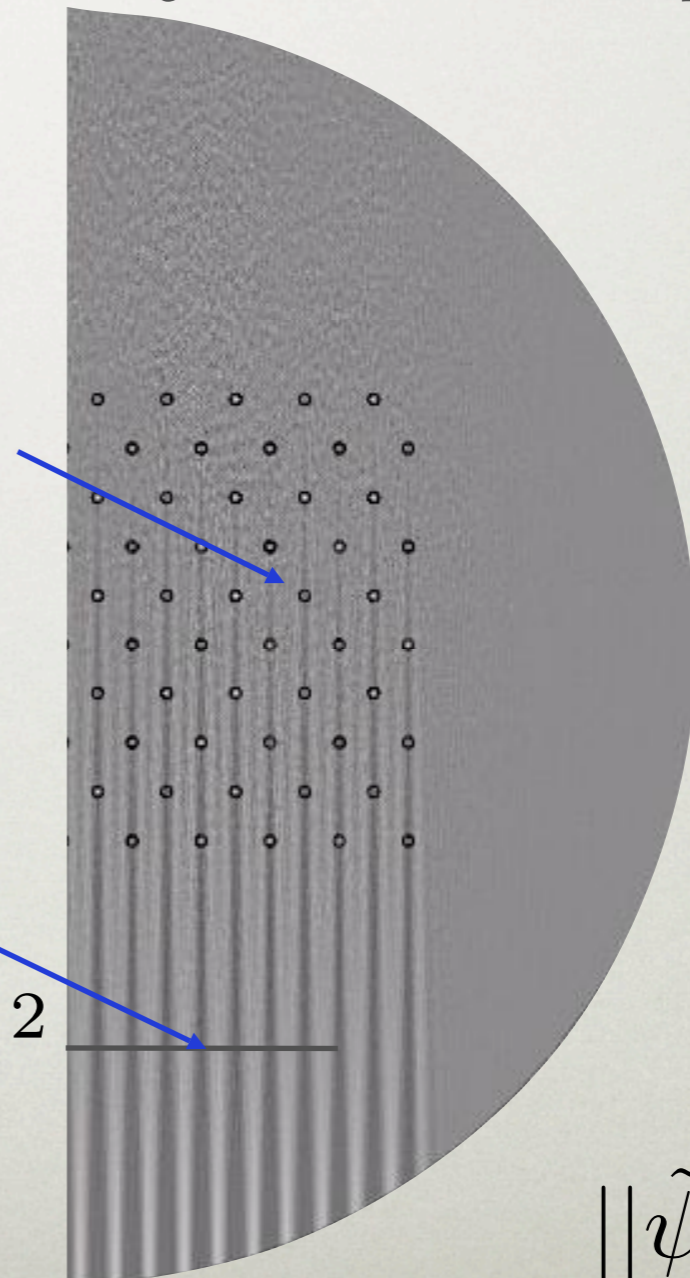
$$V_0(\mathbf{x}) = \sum_{k=1}^{N_a} K \frac{e^{-a \|\mathbf{x} - \mathbf{x}_k\|}}{\|\mathbf{x} - \mathbf{x}_k\|}$$

- Wave intensity measured on  $\Sigma_m$

- $\sim 600,000$  DOFs

$$\|\psi_m\|^2$$

$$\|\tilde{\psi}_i + \tilde{\psi}_d\|^2$$





# OUTLINE

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- TEM forward scattering
- Inverse scattering
  - Inverse problem and misfit functional
  - Adjoint state
  - Two meshes formulation
- First results



# INVERSE PROBLEM

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- Experimental data:
  - Simulated forward scattering of a sample with defects
  - Intensity on a specific virtual plane  $\Sigma_m$
- Inverse problem:
  - Search for the unknown potential associated with the measured intensity
  - Find the corresponding defects



# MISFIT FUNCTIONAL

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- **Misfit function** [Beilina *et al* 2005] [Beilina *et al* 2006]

with an additional regularization term

$$J(V) = \frac{1}{4} \int_{\Sigma_m} \left( \|\tilde{\psi}_i + \tilde{\psi}_d\|^2 - \|\psi_m\|^2 \right)^2 + \frac{\alpha}{2} \int_{\Omega_v} (V - V_0)^2$$

$V_0$ : potential of the crystal with no defects



# ADJOINT STATE

- Similar to the forward problem

$$\frac{1}{2} \Delta z + i \mathbf{k}_i^* \cdot \nabla z = 0 \text{ in } \Omega_e$$

$$\frac{\partial z}{\partial \mathbf{n}} = -i(\|\mathbf{k}_i\| + \mathbf{k}_i^* \cdot \mathbf{n})z \text{ on } \Sigma_\infty$$

- $[[dz/dn]]$  discontinuity on  $\Sigma_m$

$$\frac{1}{2} \left[ \left[ \frac{\partial z}{\partial \mathbf{n}} \right] \right] = \left( \|\tilde{\psi}_i + \tilde{\psi}_d\|^2 - \|\psi_m\|^2 \right) (\tilde{\psi}_i + \tilde{\psi}_d) \text{ on } \Sigma_m$$



# COMPATIBILITY CONDITION

- Derivative of the misfit function

$$\begin{aligned} \delta J &= \int_{\Sigma_m} \left( \|\tilde{\psi}_i + \tilde{\psi}_d\|^2 - \|\psi_m\|^2 \right) \operatorname{Re} \left( (\tilde{\psi}_i + \tilde{\psi}_d) \delta \tilde{\psi}_d^* \right) \\ &\quad + \alpha \int_{\Omega_v} (V - V_0) \delta V \\ &= \int_{\Omega_v} -\operatorname{Re}(\tilde{\psi}_i z^*) \delta V + \alpha \int_{\Omega_v} (V - V_0) \delta V \end{aligned}$$

$$\operatorname{Re}(\tilde{\psi}_i z^*) = \alpha(V - V_0) \text{ in } \Omega_e$$

$V_0$ : potential of the crystal with no defects



# NUMERICAL RESOLUTION

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Forward pb.

$$\frac{1}{2} \Delta \tilde{\psi}_d + i \mathbf{k}_i \cdot \nabla \tilde{\psi}_d = V \tilde{\psi}_i \text{ in } \Omega_e$$

$$\frac{\partial \tilde{\psi}_d}{\partial \mathbf{n}} = i(\|\mathbf{k}_i\| - \mathbf{k}_i \cdot \mathbf{n}) \tilde{\psi}_d \text{ on } \Sigma_\infty$$


---

Adjoint pb.

$$\frac{1}{2} \Delta z + i \mathbf{k}_i^* \cdot \nabla z = 0 \text{ in } \Omega_e$$

$$\frac{\partial z}{\partial \mathbf{n}} = -i(\|\mathbf{k}_i\| + \mathbf{k}_i^* \cdot \mathbf{n}) z \text{ on } \Sigma_\infty$$

$$\frac{1}{2} \left[ \left[ \frac{\partial z}{\partial \mathbf{n}} \right] \right] = \left( \|\tilde{\psi}_i + \tilde{\psi}_d\|^2 - \|\psi_m\|^2 \right) (\tilde{\psi}_i + \tilde{\psi}_d) \text{ on } \Sigma_m$$


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Compatibility

$$\text{Re}(\tilde{\psi}_i z^*) = \alpha(V - V_0) \text{ in } \Omega_e$$



# NUMERICAL RESOLUTION

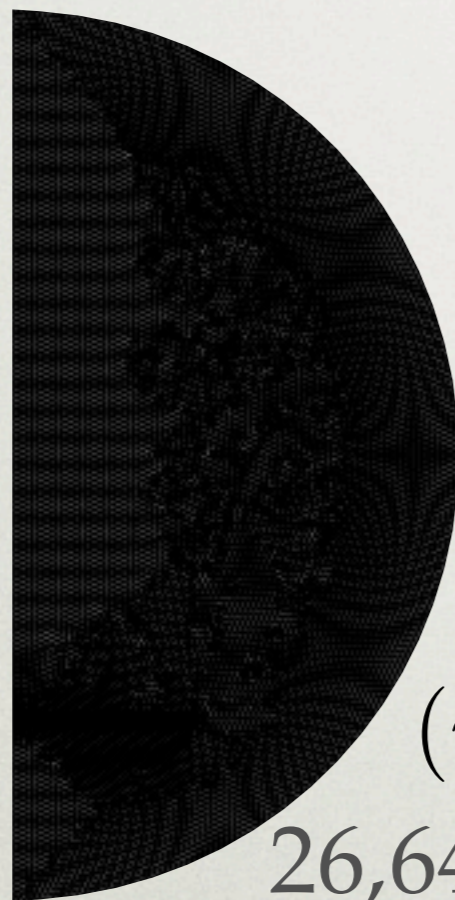
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- Problems of convergence:
  - the sought potential is discretized (FE mesh)
  - $n$  FE nodes  $\longleftrightarrow$   $n$  scalar values to identify
- Possible solutions:
  - restrict the area where the potential is sought
  - use a coarser mesh

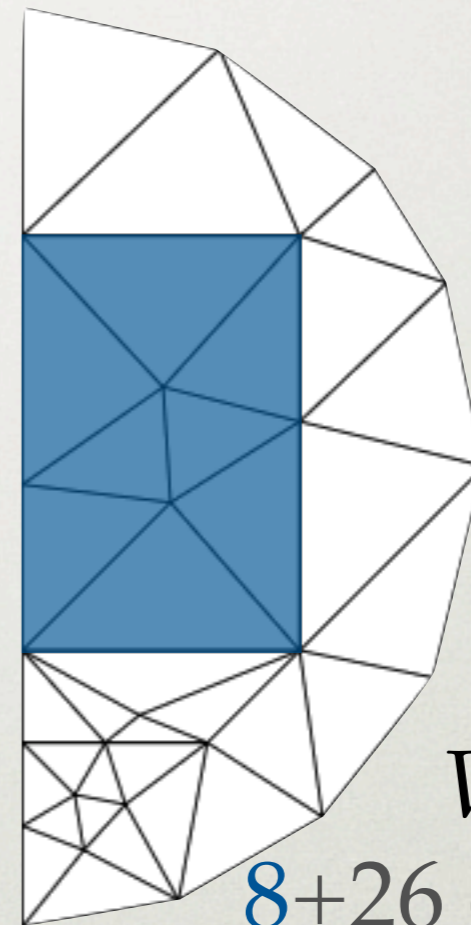


# ADAPTIVE STRATEGY

- Introduction of **two different meshes**



$(\tilde{\psi}_d, z)$   
26,645 elements



$V - V_0$   
8+26 elements

- **Adaption of the mesh** associated with  $V - V_0$
- local estimators of the misfit function  $J$  [Bangerth 2003]



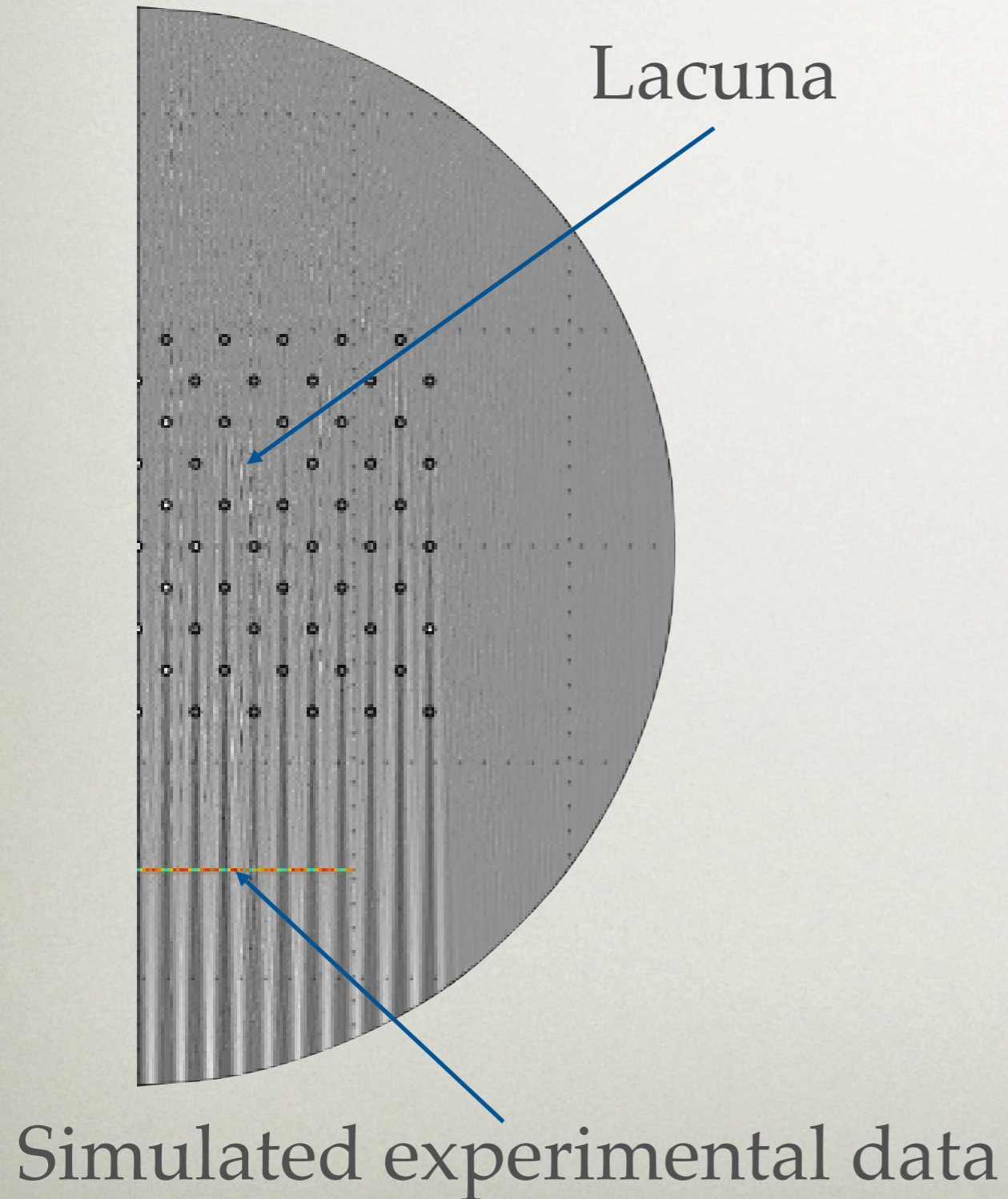
# OUTLINE

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- TEM forward scattering
- Inverse scattering
- **First results**
  - specimen with a lacuna
  - specimen with a slit

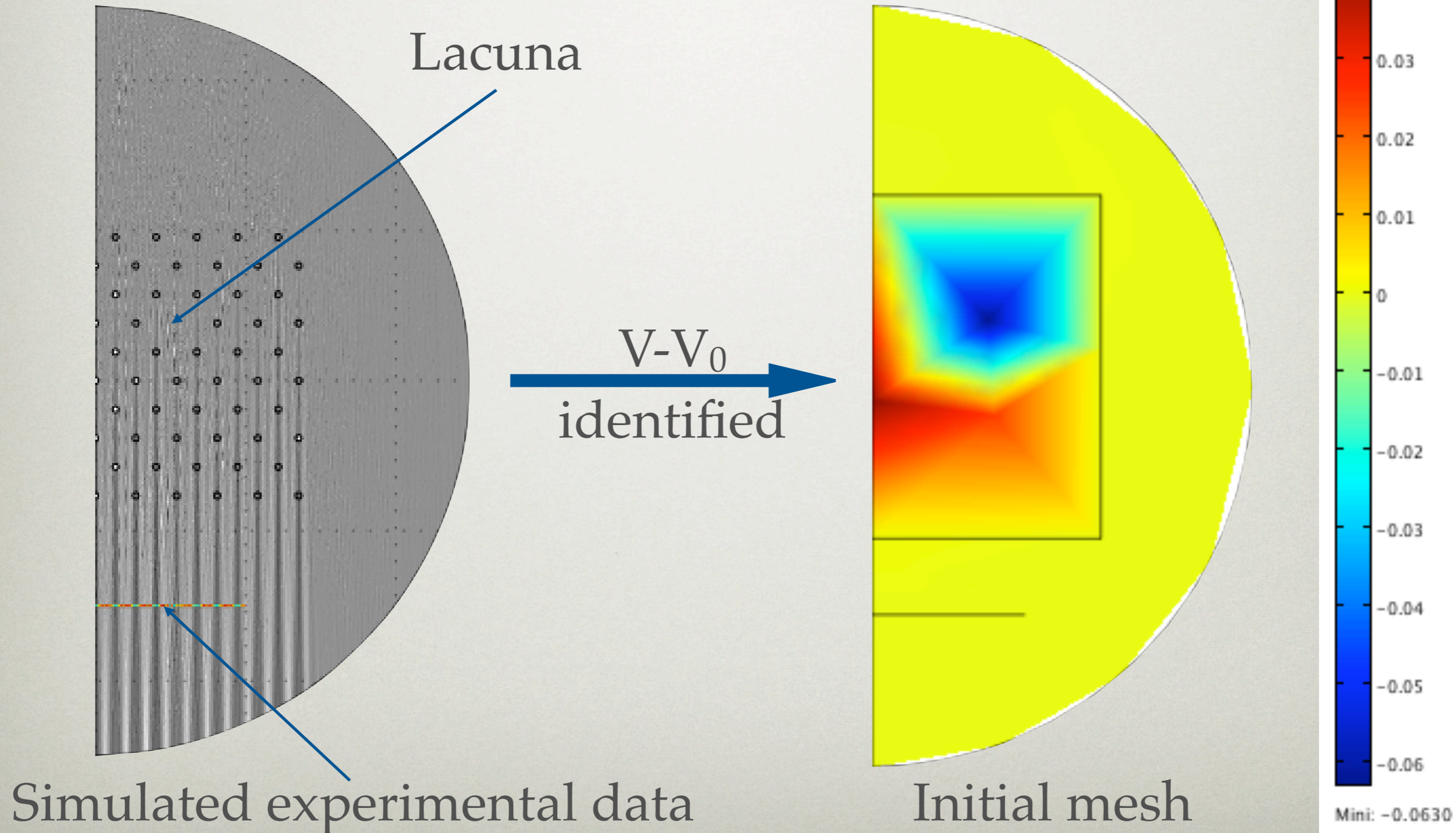


# EXAMPLE 1 ON $\alpha$ -IRON: SAMPLE WITH A LACUNA



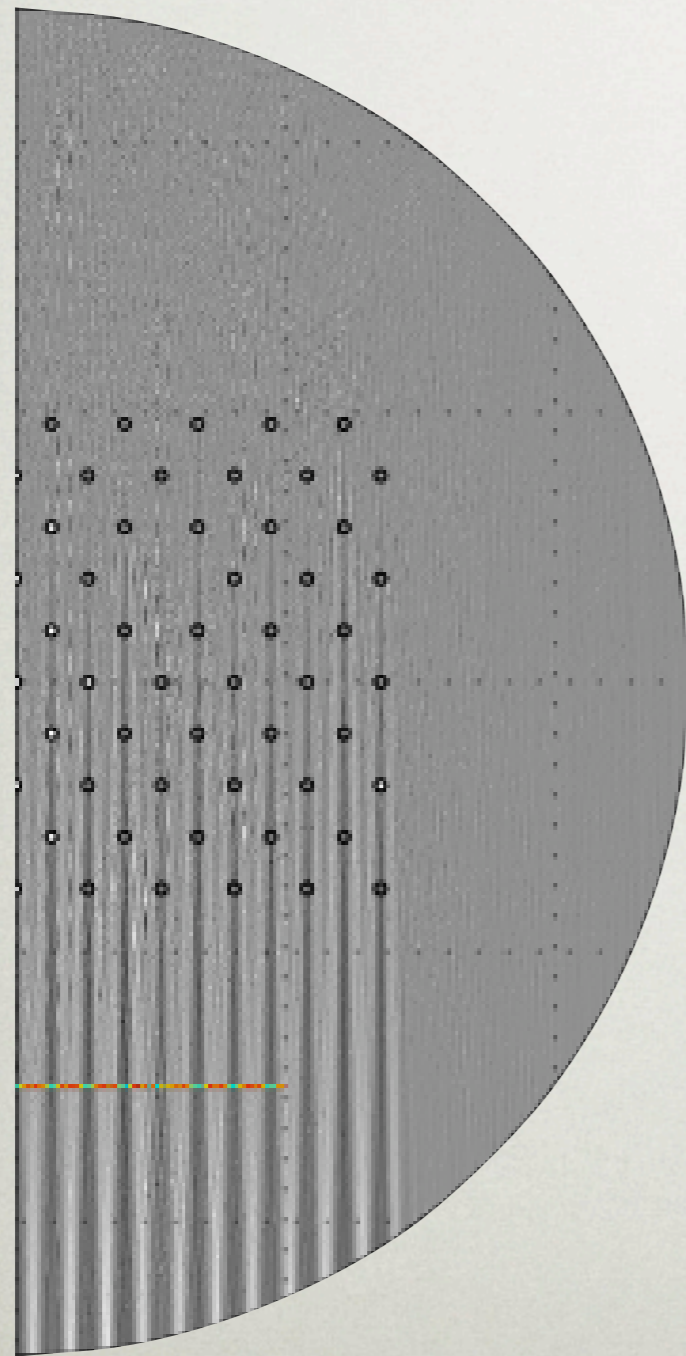


# EXAMPLE 1 ON $\alpha$ -IRON: SAMPLE WITH A LACUNA

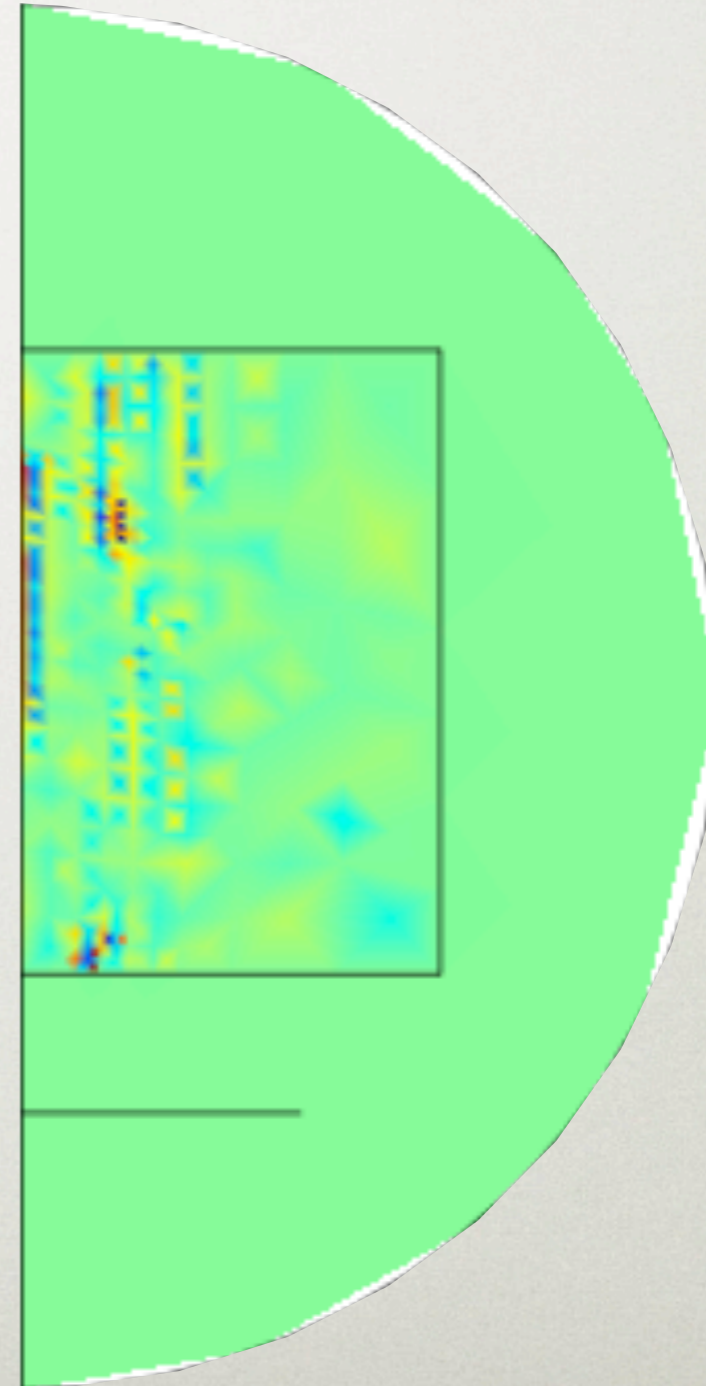




# EXAMPLE 1 ON $\alpha$ -IRON: SAMPLE WITH A LACUNA

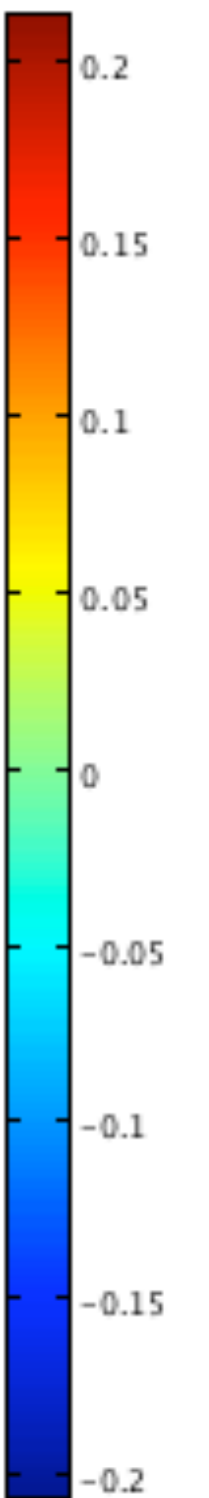


$V-V_0$   
identified



Mesh after 5 iterations

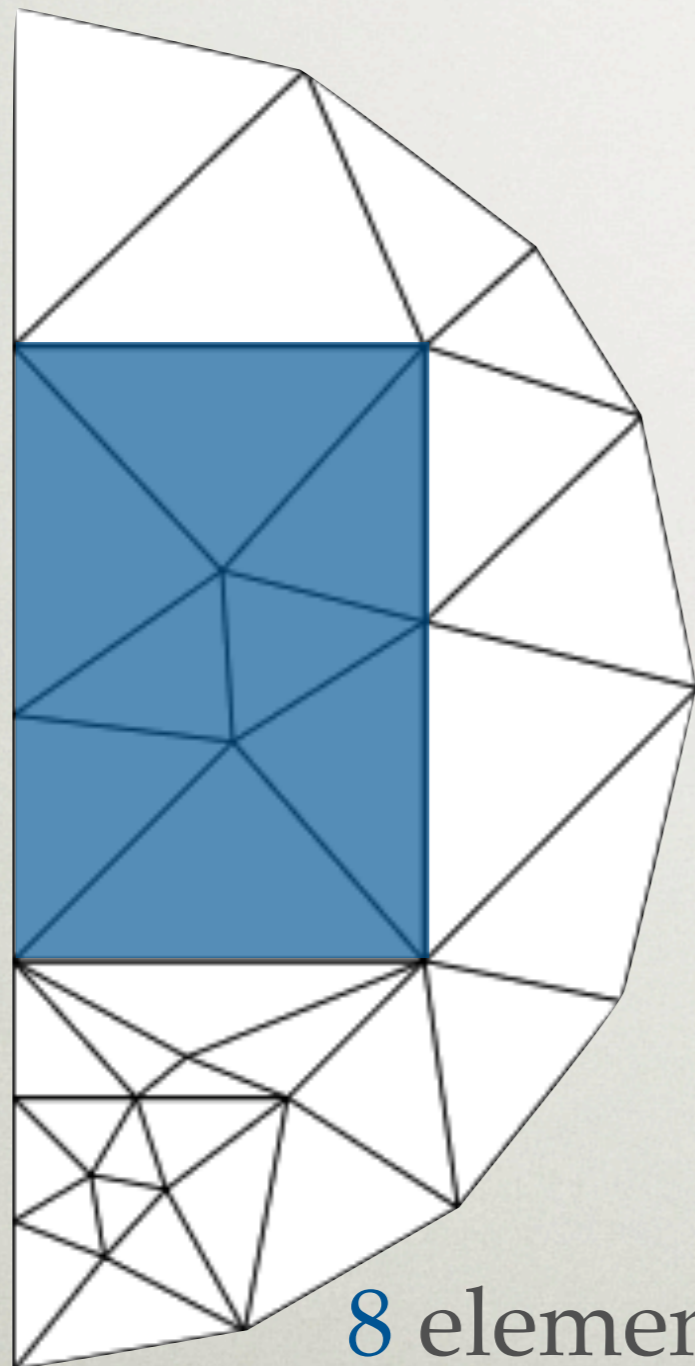
Maxi: 0.213



Mini: -0.206

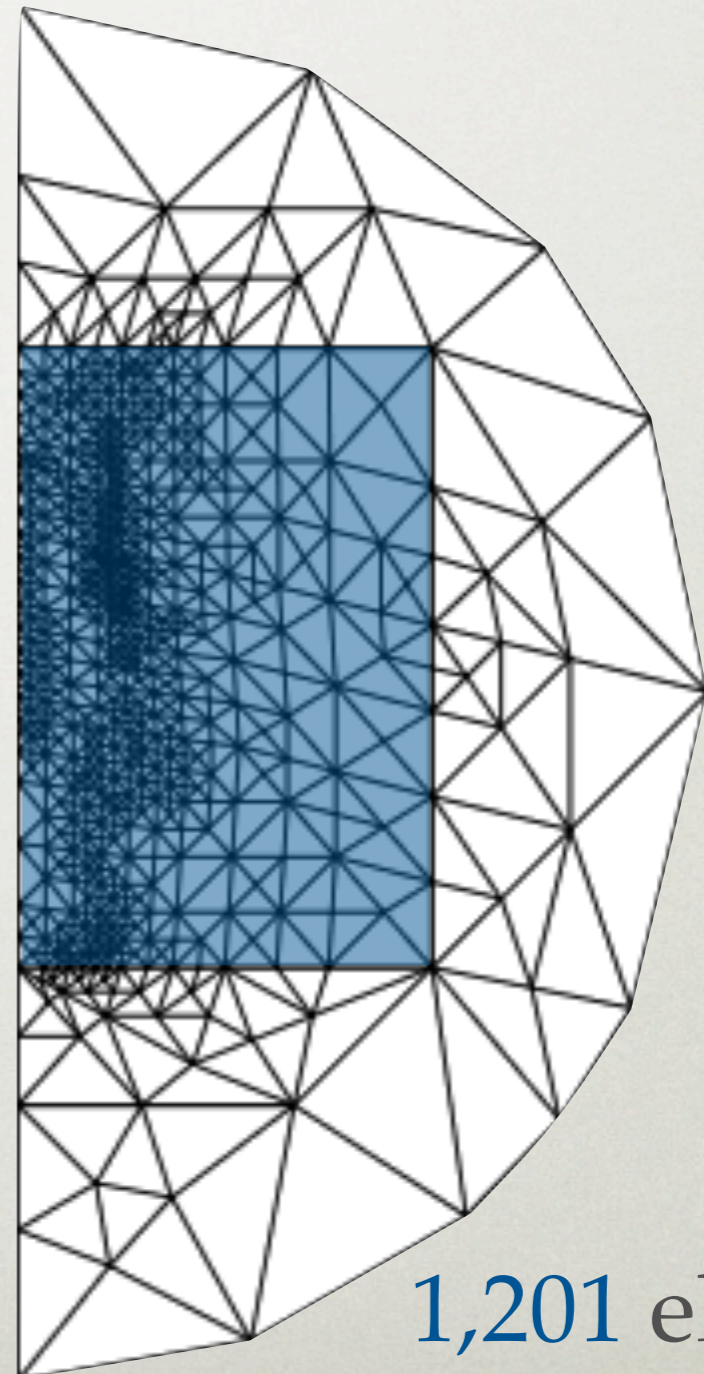
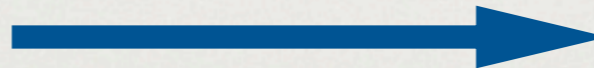


# EXAMPLE 1 ON $\alpha$ -IRON: SAMPLE WITH A LACUNA



8 elements

Initial mesh

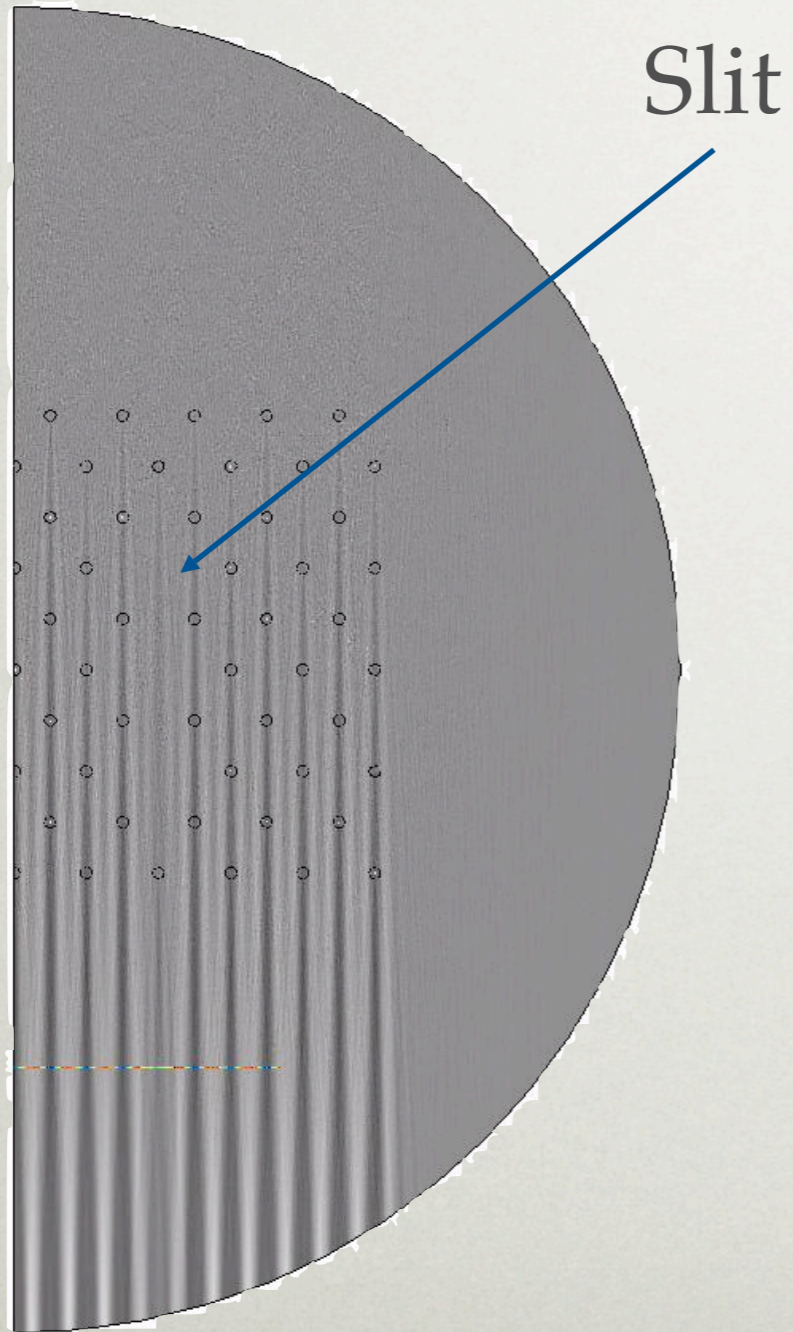


1,201 elements

Mesh after 5 iterations

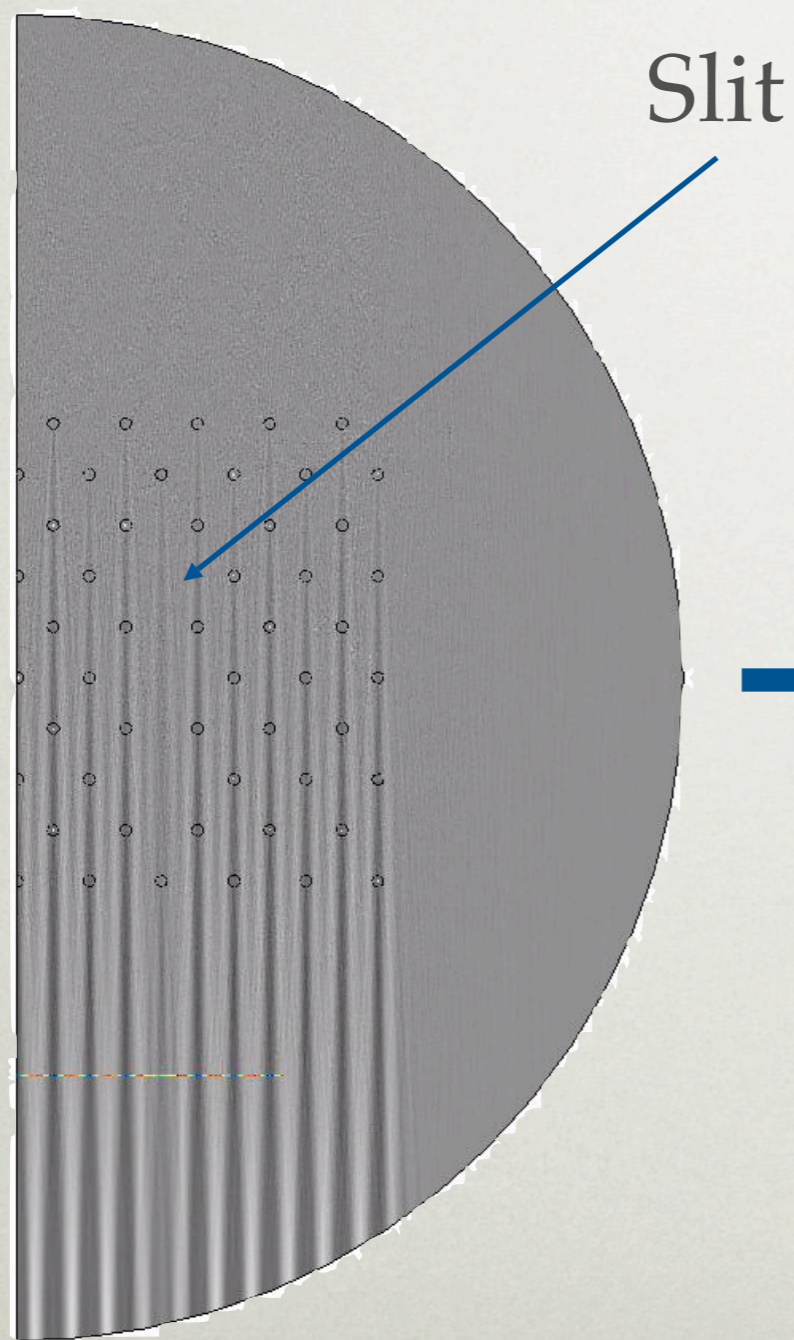


# EXAMPLE 2 ON $\alpha$ -IRON: SAMPLE WITH A SLIT

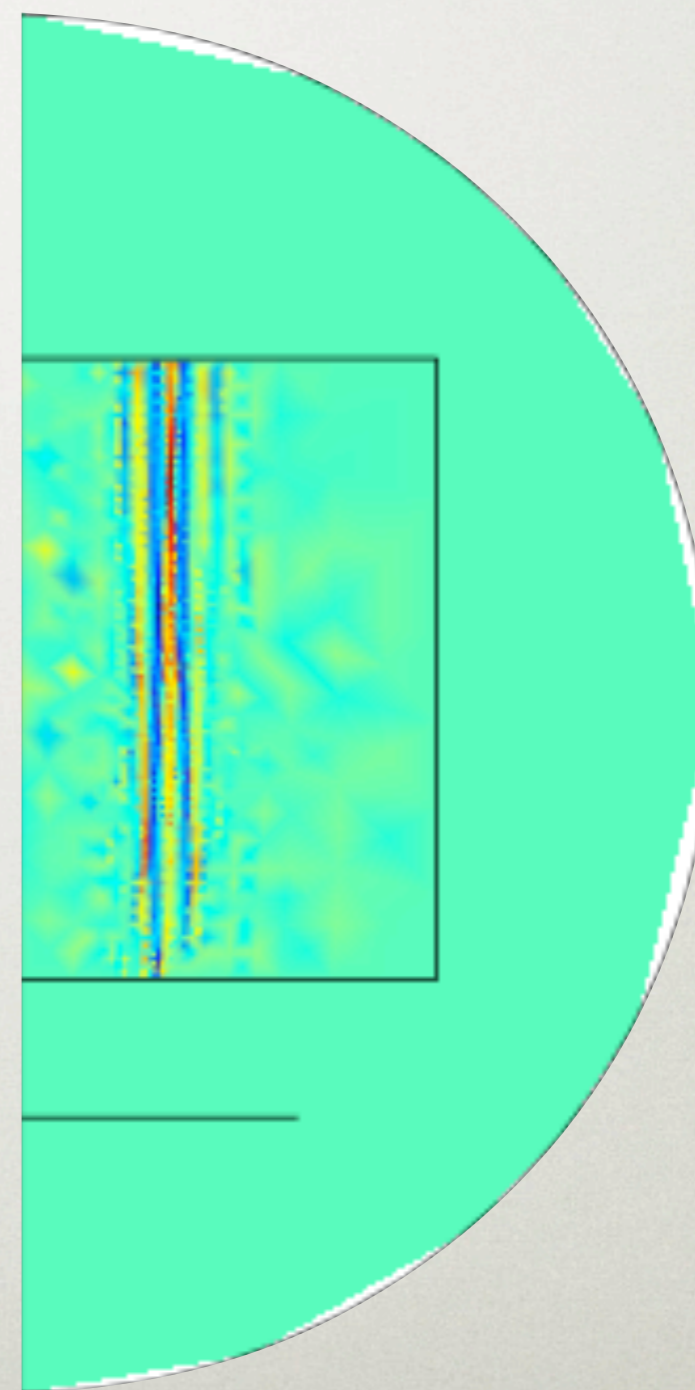




# EXAMPLE 2 ON $\alpha$ -IRON: SAMPLE WITH A SLIT



$V-V_0$   
identified



Mesh after 4 iterations

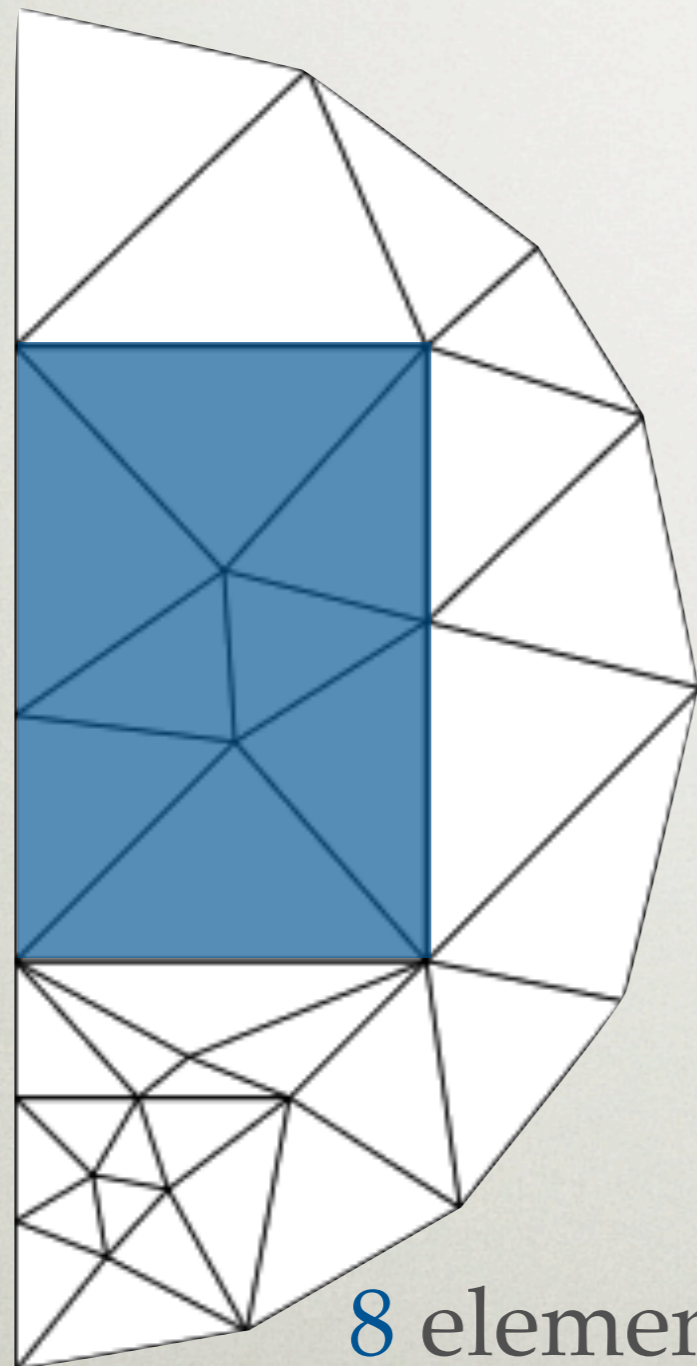
Maxi: 0.139



Mini: -0.115

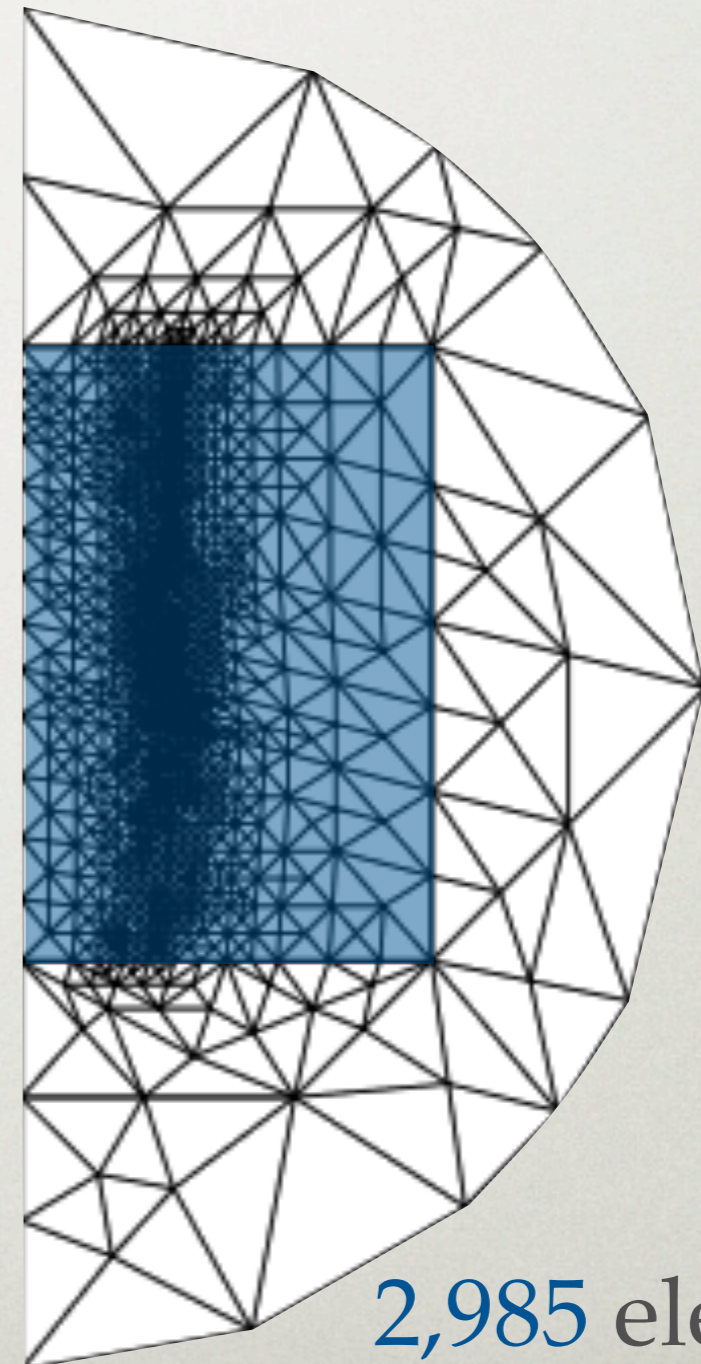
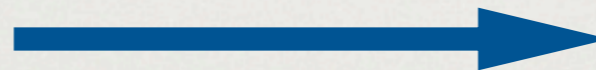


# EXAMPLE 2 ON $\alpha$ -IRON: SAMPLE WITH A SLIT



8 elements

Initial mesh



2,985 elements

Mesh after 4 iterations



# CONCLUSION

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- **Summary :**
  - iterative resolution of the inverse problem with adaptive regularization
  - first encouraging results
- **Prospects :**
  - effect of the sample size
  - use of alternative regularization terms



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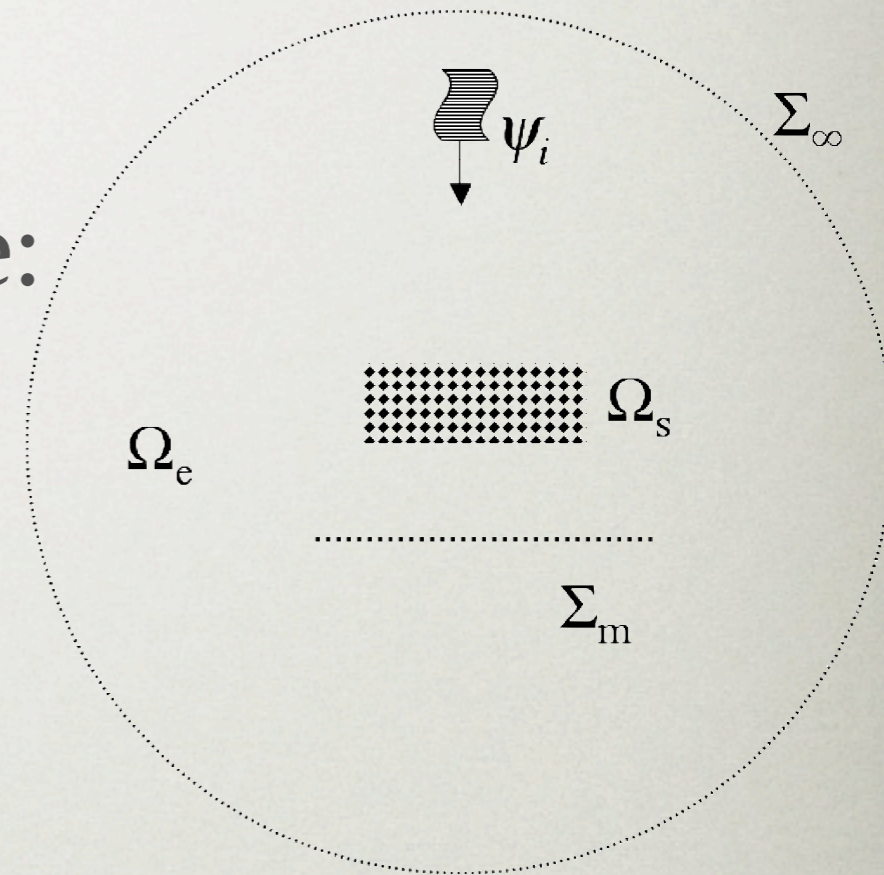
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# TEM FORWARD SCATTERING

- Schrödinger equation for incident electron and sample:
  - $\Omega_e$  with boundary  $\Sigma_\infty$
  - Sample  $\Omega_s$
  - Virtual plane  $\Sigma_m$



$$\begin{aligned}
 & -\frac{1}{2}(\Delta_{\mathbf{x}} + \Delta_{\mathbf{x}_s})\psi_{es}(\mathbf{x}, \mathbf{x}_s) \\
 & + (V_{es}(\mathbf{x}, \mathbf{x}_s) + V_s(\mathbf{x}_s))\psi_{es}(\mathbf{x}, \mathbf{x}_s) = E\psi_{es}(\mathbf{x}, \mathbf{x}_s)
 \end{aligned}$$



# TEM FORWARD SCATTERING

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- Further assumptions:

- Product of wave functions  $\psi_{es} = \psi_e \psi_s$

$$-\frac{1}{2}\Delta_{\mathbf{x}}\psi_{(e)}(\mathbf{x}) + V(\mathbf{x})\psi_{(e)}(\mathbf{x}) = (E - E_s)\psi_{(e)}(\mathbf{x})$$

- Approximation (elastic scattering)

$$-\frac{1}{2}\Delta\psi + V\psi = E_i\psi$$

- Decomposition (incident / diffracted waves)

$$-\frac{1}{2}\Delta\psi_i = E_i\psi_i \quad \psi = \psi_i + \psi_d$$

$$\frac{1}{2}\Delta\psi_d + E_i\psi_d = V\psi_i$$



# FE COMPUTATIONAL COST

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- Helmholtz type equation

$$\frac{1}{2} \Delta \psi_d + E_i \psi_d = V \psi_i$$

- Far field radiation boundary condition

$$\frac{\partial \psi_d}{\partial \mathbf{n}} = i \|\mathbf{k}_i\| \psi_d \text{ on } \Sigma_\infty$$

- Estimation of required DOFs
  - 10 elements / wavelength  $\rightarrow 10^9$  DOFs



# PARAXIAL APPROXIMATION

- Paraxial approx:  $\psi_d(\mathbf{x}) = \tilde{\psi}_d(\mathbf{x}) \exp(i\mathbf{k}_i \cdot \mathbf{x})$

$$\frac{1}{2} \Delta \psi_d + E_i \psi_d = V \psi_i$$

- Helmholtz equation:

$$\frac{1}{2} \Delta \tilde{\psi}_d + i\mathbf{k}_i \cdot \nabla \tilde{\psi}_d = V \tilde{\psi}_i \text{ in } \Omega_e$$

- Far field boundary condition:

$$\frac{\partial \psi_d}{\partial \mathbf{n}} = i \|\mathbf{k}_i\| \psi_d$$

$$\frac{\partial \tilde{\psi}_d}{\partial \mathbf{n}} = i(\|\mathbf{k}_i\| - \mathbf{k}_i \cdot \mathbf{n}) \tilde{\psi}_d \text{ on } \Sigma_\infty$$